

REVISIONS			
LTR	DESCRIPTION	DATE (YR-MO-DA)	APPROVED
A	Page 2, 1.3: Change θ_{JA} . Page 6, 4.2a(2) and 4.3.2b(2): Change T_A to T_C for burn-in and life test. Pages 7 and 8, table I: Add end-point electricals for V_{TH} . Add footnote 2/.	86-10-30	W. Heckman
B	Made technical changes to table I. Updated drawing format with editorial changes. Added device types 02 through 07. Added cases Y, Z, U, and T. Changed to reflect MIL-H-38534 processing. Device type 01 inactive for new design. Added current CAGE code 67268 to sheet 1.	90-02-09	W. Heckman
C	Add device type 08. Made technical changes to table I. Change dimensions for case outline Y. Change dimensions for case outline U. Editorial changes throughout.	94-01-14	K. Cottongim
D	Changes in accordance with NOR 5962-R170-95.	95-07-12	Kendall A. Cottongim
E	Update drawing boilerplate to most current format.	02-02-25	Raymond Monnin

THE ORIGINAL FIRST PAGE OF THIS DRAWING HAS BEEN REPLACED.

CURRENT CAGE CODE 67268

1. SCOPE

1.1 Scope. This drawing describes device requirements for class H hybrid microcircuits to be processed in accordance with MIL-PRF-38534 and a choice of case outlines and lead finishes are available and are reflected in the Part or Identifying Number (PIN).

1.2 PIN. The PIN shall be as shown in the following example:



1.2.1 Device type(s). The device type(s) shall identify the circuit function as follows:

<u>Device type</u>	<u>Generic number</u>	<u>Circuit function</u>
01	BUS-63105	Single channel driver-receiver
02	BUS-63105II, BUS-63106II	Low power, single channel driver-receiver
03	ARX2402	Single channel driver-receiver
04	ARX3402	Low power, single channel driver-receiver
05	CT-1487M, BUS-8553, BUS-63100	Single channel driver-receiver
06	NHI-1509	Single channel driver-receiver
07	FC155361	Single channel driver-receiver
08	FC155362	Single channel driver-receiver

1.2.2 Case outline(s). The case outline(s) shall be as designated in MIL-STD-1835 and as follows:

<u>Outline letter</u>	<u>Descriptive designator</u>	<u>Terminals</u>	<u>Package style</u>
T	See figure 1	24	Flat package
U	See figure 1	24	Dual-in-line package
X	See figure 1	24	Dual-in-line package
Y	See figure 1	24	Dual-in-line package
Z	See figure 1	24	Dual-in-line package

1.2.3 Lead finish. The lead finish shall be as specified in MIL-PRF-38534.

**STANDARD
MICROCIRCUIT DRAWING**

DEFENSE SUPPLY CENTER COLUMBUS
COLUMBUS, OHIO 43216-5000

**SIZE
A**

5962-86409

**REVISION LEVEL
E**

**SHEET
2**

1.3 Absolute maximum ratings. 1/

Supply voltage range:	
V _{CC} (device types 01, 03, 04, 05, 06, 07, and 08)	-0.3 V dc to +18 V dc
V _{EE} (device types 01, 02, 03, 04, 05, 07, and 08)	+0.3 V dc to -18 V dc
V _{CC1}	-0.3 V dc to +7 V dc
Logic input voltage range	-0.3 V dc to V _{CC1}
Receiver differential voltage	40 Vp-p
Receiver common mode voltage range.....	-10 V dc to +10 V dc
Driver peak output current.....	200 mA
Power dissipation (P _D) at +125°C:	
Device types 01, 05, 07, and 08	4 W
Device type 02	2.5 W
Device type 03	2.2 W
Device type 04	1.6 W
Device type 06	0.585 W
Storage temperature range	-65°C to +150°C
Lead temperature (soldering, 10 seconds)	+300°C
Junction temperature (T _J)	+160°C
Thermal resistance, junction-to-case (θ _{JC}):	
Device types 01, 06, 07, and 08	8.8°C/W
Device type 02	7.0°C/W
Device type 03	47.2°C/W
Device type 04	88°C/W
Device type 05	60°C/W
Thermal resistance, junction to ambient (θ _{JA}):	
Device types 01, 06, 07, and 08	38.8°C/W
Device type 02.....	37.0°C/W
Device type 03	77.2°C/W
Device type 04	110°C/W
Device type 05	80°C/W

1.4 Recommended operating conditions.

Supply voltage range:	
V _{CC} (device types 01, 03, 04, 05, 06, 07, and 08)	+14.25 V dc to +15.75 V dc
V _{EE} (device types 01, 02, 03, 04, 05, 07, and 08)	-14.25 V dc to -15.75 V dc
V _{CC1}	+4.5 V dc to +5.5 V dc
Logic input voltage range	0 V dc to +5.0 V dc
Receiver differential voltage	30 Vp-p
Receiver common mode voltage range.....	-5.0 V dc to +5.0 V dc
Driver peak output current:	
Device types 01, 03, 04, 05, 06, 07, and 08	180 mA
Device type 02.....	160 mA
Serial data rate	1.0 MHz maximum
Junction temperature (T _J)	+150°C maximum
Case operating temperature range (T _C)	-55°C to +125°C

1/ Stresses above the absolute maximum rating may cause permanent damage to the device. Extended operation at the maximum levels may degrade performance and affect reliability.

STANDARD MICROCIRCUIT DRAWING DEFENSE SUPPLY CENTER COLUMBUS COLUMBUS, OHIO 43216-5000	SIZE	5962-86409
	E	

2. APPLICABLE DOCUMENTS

2.1 Government specification, standards, and handbooks. The following specification, standards, and handbooks form a part of this drawing to the extent specified herein. Unless otherwise specified, the issues of these documents are those listed in the issue of the Department of Defense Index of Specifications and Standards (DoDISS) and supplement thereto, cited in the solicitation.

SPECIFICATION

DEPARTMENT OF DEFENSE

MIL-PRF-38534 - Hybrid Microcircuits, General Specification for.

STANDARDS

DEPARTMENT OF DEFENSE

MIL-STD-883 - Test Method Standard Microcircuits.

MIL-STD-1835 - Interface Standard for Microcircuit Case Outlines.

HANDBOOKS

DEPARTMENT OF DEFENSE

MIL-HDBK-103 - List of Standard Microcircuit Drawings (SMD's).

MIL-HDBK-780 - Standard Microcircuit Drawings.

MIL-HDBK-1553 - Multiplex Application Handbook.

(Unless otherwise indicated, copies of the specification, standards, and handbooks are available from the Standardization Document Order Desk, 700 Robbins Avenue, Building 4D, Philadelphia, PA 19111-5094.)

2.2 Order of precedence. In the event of a conflict between the text of this drawing and the references cited herein, the text of this drawing takes precedence. Nothing in this document, however, supersedes applicable laws and regulations unless a specific exemption has been obtained.

3. REQUIREMENTS

3.1 Item requirements. The individual item performance requirements for device class H shall be in accordance with MIL-PRF-38534. Compliance with MIL-PRF-38534 may include the performance of all tests herein or as designated in the device manufacturer's Quality Management (QM) plan or as designated for the applicable device class. Therefore, the tests and inspections herein may not be performed for the applicable device class (see MIL-PRF-38534). Furthermore, the manufacturers may take exceptions or use alternate methods to the tests and inspections herein and not perform them. However, the performance requirements as defined in MIL-PRF-38534 shall be met for the applicable device class.

3.2 Design, construction, and physical dimensions. The design, construction, and physical dimensions shall be as specified in MIL-PRF-38534 and herein.

3.2.1 Case outline(s). The case outline(s) shall be in accordance with 1.2.2 herein and figure 1.

3.2.2 Terminal connections. The terminal connections shall be as specified on figure 2.

3.2.3 Waveforms. The waveforms shall be as specified on figure 3.

3.3 Electrical performance characteristics. Unless otherwise specified herein, the electrical performance characteristics are as specified in table I and shall apply over the full specified operating temperature range.

STANDARD MICROCIRCUIT DRAWING DEFENSE SUPPLY CENTER COLUMBUS COLUMBUS, OHIO 43216-5000	SIZE A	REVISION LEVEL E	5962-86409
			4

3.4 Electrical test requirements. The electrical test requirements shall be the subgroups specified in table II. The electrical tests for each subgroup are defined in table I.

3.5 Marking of device(s). Marking of device(s) shall be in accordance with MIL-PRF-38534. The device shall be marked with the PIN listed in 1.2 herein. In addition, the manufacturer's vendor similar PIN may also be marked.

3.6 Data. In addition to the general performance requirements of MIL-PRF-38534, the manufacturer of the device described herein shall maintain the electrical test data (variables format) from the initial quality conformance inspection group A lot sample, for each device type listed herein. Also, the data should include a summary of all parameters manually tested, and for those which, if any, are guaranteed. This data shall be maintained under document revision level control by the manufacturer and be made available to the preparing activity (DSCC-VA) upon request.

3.7 Certificate of compliance. A certificate of compliance shall be required from a manufacturer in order to supply to this drawing. The certificate of compliance (original copy) submitted to DSCC-VA shall affirm that the manufacturer's product meets the performance requirements of MIL-PRF-38534 and herein.

3.8 Certificate of conformance. A certificate of conformance as required in MIL-PRF-38534 shall be provided with each lot of microcircuits delivered to this drawing.

4. QUALITY ASSURANCE PROVISIONS

4.1 Sampling and inspection. Sampling and inspection procedures shall be in accordance with MIL-PRF-38534 or as modified in the device manufacturer's Quality Management (QM) plan. The modification in the QM plan shall not affect the form, fit, or function as described herein.

4.2 Screening. Screening shall be in accordance with MIL-PRF-38534. The following additional criteria shall apply:

a. Burn-in test, method 1015 of MIL-STD-883.

(1) Test condition A, B, C, or D. The test circuit shall be maintained by the manufacturer under document revision level control and shall be made available to either DSCC-VA or the acquiring activity upon request. Also, the test circuit shall specify the inputs, outputs, biases, and power dissipation, as applicable, in accordance with the intent specified in test method 1015 of MIL-STD-883.

(2) TA as specified in accordance with table I of method 1015 of MIL-STD-883.

b. Interim and final electrical test parameters shall be as specified in table II herein, except interim electrical parameter tests prior to burn-in are optional at the discretion of the manufacturer.

STANDARD MICROCIRCUIT DRAWING DEFENSE SUPPLY CENTER COLUMBUS COLUMBUS, OHIO 43216-5000	SIZE A	REVISION LEVEL E	5962-86409
			5

TABLE I. Electrical performance characteristics.

Test	Symbol	Conditions 1/ -55°C ≤ T _C ≤ +125°C unless otherwise specified	Group A subgroups	Device type	Limits		Unit
					Min	Max	
Receiver							
Input level	V _I	Differential input, pin 15 to pin 16 2/	4,5,6	All	40		V _{p-p}
Input common mode voltage range	V _{ICM}	Independent of xfmr or in accordance with MIL-HDBK-1553 2/	4,5,6	All	-5	+5	V(pk)
Output low voltage	V _{OL}	I _{OL} = 16 mA	1,2,3	01,02		0.5	V
		I _{OL} = 4 mA		03,04,05, 06,07,08		0.5	
Output high voltage	V _{OH}	I _{OH} = -0.4 mA	1,2,3	01,03,04, 05,06,07, 08	2.5		V
				02	2.4		
Transmitter							
Input voltage low	V _{IL}	3/	1,2,3	All		0.7	V
Input voltage high	V _{IH}	3/	1,2,3	All	2		V
Input current low	I _{IL}	V _{IL} = 0.4 V	1,2,3	01,03,05, 07,08	-1.6		mA
				02	-0.72	0.04	
				04,06	-0.4		
Input current high	I _{IH}	V _{IH} = 2.7 V	1,2,3	01,03,04, 05,06,07, 08		0.04	mA
				02	-0.72	0.04	
Output voltage	V _O	Across 35Ω load	1,2,3	All	6	9	V _{p-p}
Output noise voltage	V _{ON}	Across 35Ω load	4,5,6	All		10	mV _{p-p}
See footnotes at end of table.							
STANDARD MICROCIRCUIT DRAWING DEFENSE SUPPLY CENTER COLUMBUS COLUMBUS, OHIO 43216-5000				SIZE A			5962-86409
					REVISION LEVEL E		SHEET 6

TABLE I. Electrical performance characteristics - Continued.

Test	Symbol	Conditions 1/ -55°C ≤ T _C ≤ +125°C unless otherwise specified	Group A subgroups	Device type	Limits		Unit			
					Min	Max				
Receiver strobe										
Input voltage low	V _{SIL}	3/	1,2,3	All		0.7	V			
Input voltage high	V _{SIH}	3/, in accordance with MIL-HDBK-1553 2/	1,2,3	All	2		V			
Input current low	I _{SIL}	V _{IL} = 0.4 V	1,2,3	01,05, 07,08	-1.6		mA			
				02	-0.72	0.4				
				03,06	-0.8					
				04	-0.4					
Input current high	I _{SIH}	V _{IH} = 2.7 V	1,2,3	01,03,04, 05,06,07, 08		0.04	mA			
				02	-0.72	0.04				
Transmitter inhibit										
Input voltage low	V _{IIL}	3/	1,2,3	All		0.7	V			
Input voltage high	V _{IIH}	3/	1,2,3	All	2		V			
Input current low	I _{IIL}	V _{SIL} = 0.4 V	1,2,3	01,03,05, 07,08	-1.6		mA			
				02	-0.72	0.04				
				04,06	-0.4					
				01,03,04, 05,06,07, 08		0.04				
Input current high	I _{IIH}	V _{SIH} = 2.7 V	1,2,3	02	-0.72	0.04	mA			
See footnotes at end of table.										
STANDARD MICROCIRCUIT DRAWING DEFENSE SUPPLY CENTER COLUMBUS COLUMBUS, OHIO 43216-5000				SIZE A			5962-86409			
					REVISION LEVEL E		SHEET 7			

TABLE I. Electrical performance characteristics - Continued.

Test	Symbol	Conditions 1/ -55°C ≤ T _C ≤ +125°C unless otherwise specified	Group A subgroups	Device type	Limits		Unit
					Min	Max	
Power supply							
Total current	I _{CC-SB}	(Standby mode)	1,2,3	01,07,08		50	mA
				03		40	
				04		1	
				05,06		25	
	I _{EE-SB}	(Standby mode)	1,2,3	01,07,08		50	mA
				02		35	
				03		30	
				04		16.5	
				05		35	
	I _{CC1-SB}	(Standby mode)	1,2,3	01,07,08		35	mA
				02,05		45	
				03		20	
				04,06		30	
	I _{CC-25}	(25% duty cycle into 35Ω load)	1,2,3	01,07,08		65	mA
				03		90	
				05,06		75	
				04		55	
	I _{EE-25}	(25% duty cycle into 35Ω load)	1,2,3	01,07,08		95	mA
				02 2/		80	
				03		30	
				04		21	
				05		35	
	I _{CC1-25}	(25% duty cycle into 35Ω load)	1,2,3	01,07,08		35	mA
				02 2/		45	
				05		45	
				03		20	
				04,06		30	
	I _{CC-50}	(50% duty cycle into 35Ω load)	1,2,3	01,07,08		140	mA
				03		140	
				04		110	
				05,06		130	
	I _{EE-50}	(50% duty cycle into 35Ω load)	1,2,3	01,07,08		50	mA
				02		130	
				03		30	
				04		25	
				05		35	

See footnotes at end of table.

STANDARD MICROCIRCUIT DRAWING DEFENSE SUPPLY CENTER COLUMBUS COLUMBUS, OHIO 43216-5000	SIZE A	5962-86409
	REVISION LEVEL E	

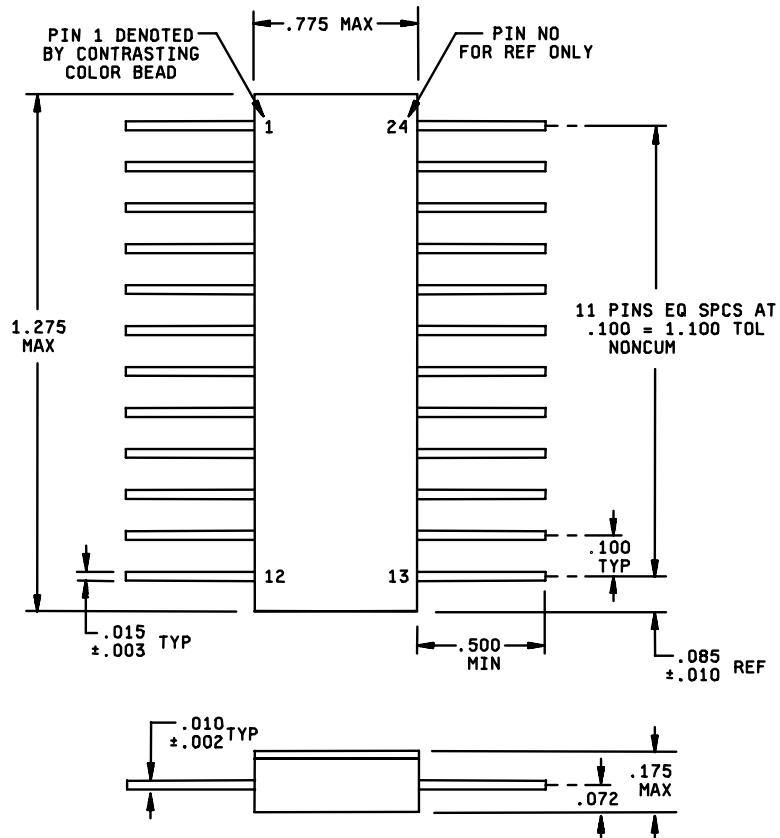
TABLE I. Electrical performance characteristics - Continued.

Test	Symbol	Conditions 1/ -55°C ≤ T _C ≤ +125°C unless otherwise specified	Group A subgroups	Device type	Limits		Unit		
					Min	Max			
Power supply - Continued.									
Total current	I _{CC1} -50	(50% duty cycle into 35Ω load)	4,5,6	01,07,08		35	mA		
				02,05		45			
				03		20			
				04,06		30			
	I _{CC} -100	(100% duty cycle into 35Ω load)	1,2,3	01,07,08		240	mA		
				03		240			
				04,06		220			
				05		235			
	I _{EE} -100	(100% duty cycle into 35Ω load)	1,2,3	01,07,08		50	mA		
				02 2/		225			
				03,04		30			
				05		35			
	I _{CC1} -100	(100% duty cycle into 35Ω load)	1,2,3	01,07,08		35	mA		
				02 2/		45			
				05		45			
				03		20			
				04,06		30			
Receiver									
Input resistance	R _{IN}	1 MHz sine wave 2/	4,5,6	All	7		kΩ		
Input capacitance	C _{IN}	1 MHz sine wave 2/	4	All		5	pF		
Threshold voltage	V _{TH}	4/	1,2,3,	01,02,03, 04,05,06	0.56	1.05	Vp-p		
				07,08	0.80	1.2			
			1,2,3	01,03,04, 05,06,07, 08	0.50	1.1			
				02	0.56	1.0			
See footnotes at end of table.									
STANDARD MICROCIRCUIT DRAWING DEFENSE SUPPLY CENTER COLUMBUS COLUMBUS, OHIO 43216-5000			SIZE A			5962-86409			
					REVISION LEVEL E	SHEET 9			

TABLE I. Electrical performance characteristics - Continued.

Test	Symbol	Conditions 1/ -55°C ≤ T _C ≤ +125°C unless otherwise specified	Group A subgroups	Device type	Limits		Unit			
					Min	Max				
Transmitter										
Output resistance (transmitter off)	R _{OUT}	1 MHz sine wave 2/	4,5,6	All	10		kΩ			
Output capacitance (transmitter off)	C _{OUT}	1 MHz sine wave 2/	4	All		5	pF			
Output offset voltage	V _{OS}	2/ 5/	4,5,6	All		±90	mV pk			
Peak amplitude variation	A _V	2/ 6/	4,5,6	01,03,04, 05,06,07, 08	-15	+15	%			
Receiver										
Delay time, input to output	t _{DR}	Delay time from differential input zero crossing to DATA or DATA 2/ (see figure 3)	9,10,11	All		400	ns			
Strobe delay	t _{DS}	Delay time from strobe rising or falling edge to DATA or DATA 2/ (see figure 3)	9,10,11	01,02,03, 05,06,07, 08	200		ns			
				04		250				
Transmitter										
Rise time	t _R	Output load = 35Ω (see figure 3)	9,10,11	All	100	300	ns			
Fall time	t _F			All	100	300				
Delay time	t _{DT}	Output load = 35Ω (see figure 3) 2/	9,10,11	01,02,05, 07,08		250	ns			
				04		350				
				03,06		150				
Inhibit delay inhibiting	t _{DI-H}	Output load = 35Ω (see figure 3) 2/	9,10,11	01,02,04, 05,07,08		450	ns			
				03,06		200				
Inhibit delay active	t _{DI-L}	Output load = 35Ω (see figure 3) 2/	9,10,11	01,02,04, 05,07,08		250	ns			
				03,06		100				
1/	V _{CC} = +15 V, for device types 01, 03, 04, 05, 06, 07, and 08, V _{EE} = -15 V for device types 01, 02, 03, 04, 05, 07, and 08, V _{CC1} = +5 V.									
2/	This parameter is tested initially and after any process or design change which may affect this parameter.									
3/	These parameters are tested on a go-no-go basis in conjunction with other measured parameters and are not directly testable.									
4/	Threshold is measured in direct coupled mode including the transformer. Threshold is the maximum level on the BUS at which there are no pulses on either receiver output. Divide by 1.4 to obtain threshold in transformer coupled mode. Add 0.14 V in direct coupled mode or 0.10 V in transformer coupled mode to obtain threshold at which no errors are observed when receiver is used with 15530 CMOS Manchester encoder-decoder.									
5/	Measured across 35Ω load, 2.5 μs after parity bit mid-bit zero crossing of a 660 microseconds message.									
6/	Measured across 35Ω load, variation of average peak amplitude.									
STANDARD MICROCIRCUIT DRAWING DEFENSE SUPPLY CENTER COLUMBUS COLUMBUS, OHIO 43216-5000				SIZE A			5962-86409			
					REVISION LEVEL E		SHEET 10			

Case outline T.
(Device types 02 and 06)

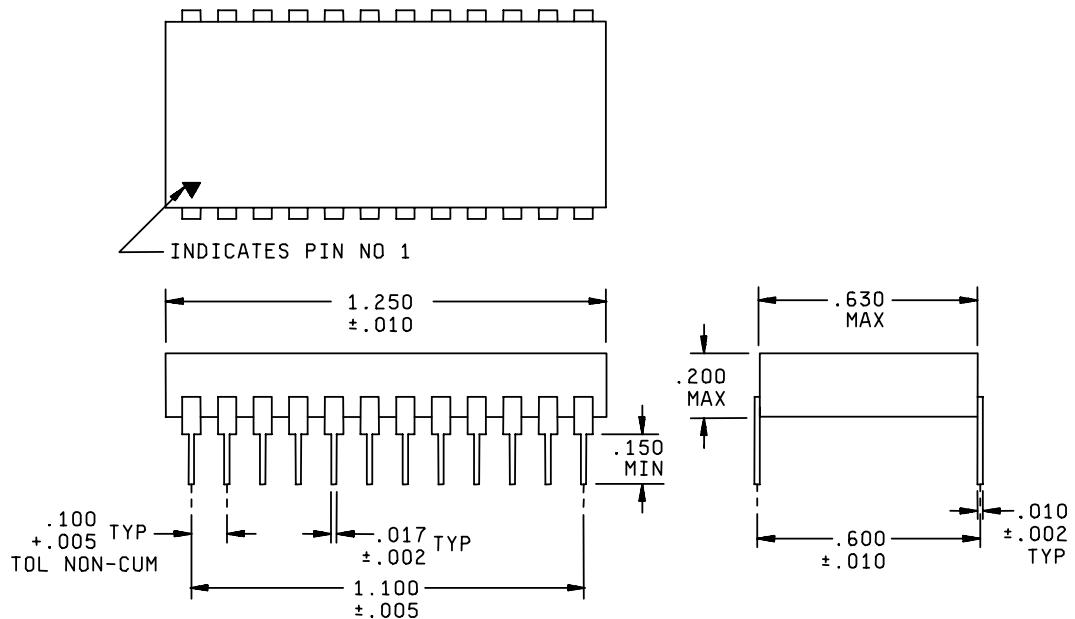


Inches	mm
.002	0.05
.003	0.08
.010	0.25
.015	0.38
.072	1.83
.085	2.16
.100	2.54
.175	4.45
.500	12.70
.775	19.68
1.100	27.94
1.275	32.39

FIGURE 1. Case outline(s).

STANDARD MICROCIRCUIT DRAWING DEFENSE SUPPLY CENTER COLUMBUS COLUMBUS, OHIO 43216-5000	SIZE A	5962-86409
	REVISION LEVEL E	

Case outline U.
(Device type 04)



Inches	mm
.002	0.05
.005	0.13
.010	0.25
.017	0.43
.100	2.54
.150	3.81
.200	5.08
.600	15.24
.630	16.00
1.100	27.94
1.250	31.75

FIGURE 1. Case outline(s) - Continued.

**STANDARD
MICROCIRCUIT DRAWING**

DEFENSE SUPPLY CENTER COLUMBUS
COLUMBUS, OHIO 43216-5000

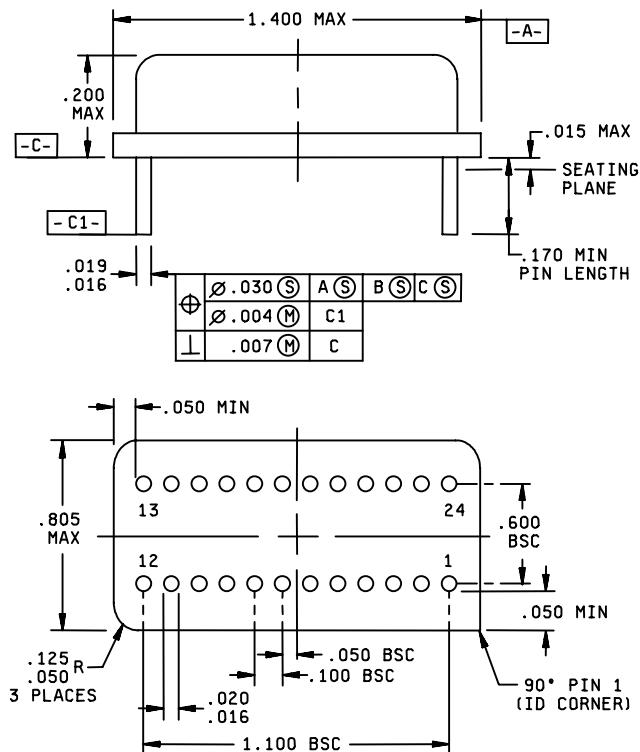
**SIZE
A**

5962-86409

REVISION LEVEL
E

SHEET
12

Case outline X.
(Device types 01, 05, 07, and 08)



Inches	mm	Inches	mm
.004	0.10	.100	2.54
.007	0.18	.125	3.18
.015	0.38	.170	4.32
.016	0.41	.200	5.08
.019	0.48	.600	15.24
.020	0.50	.805	20.45
.030	0.76	1.100	27.94
.050	1.27	1.400	35.56

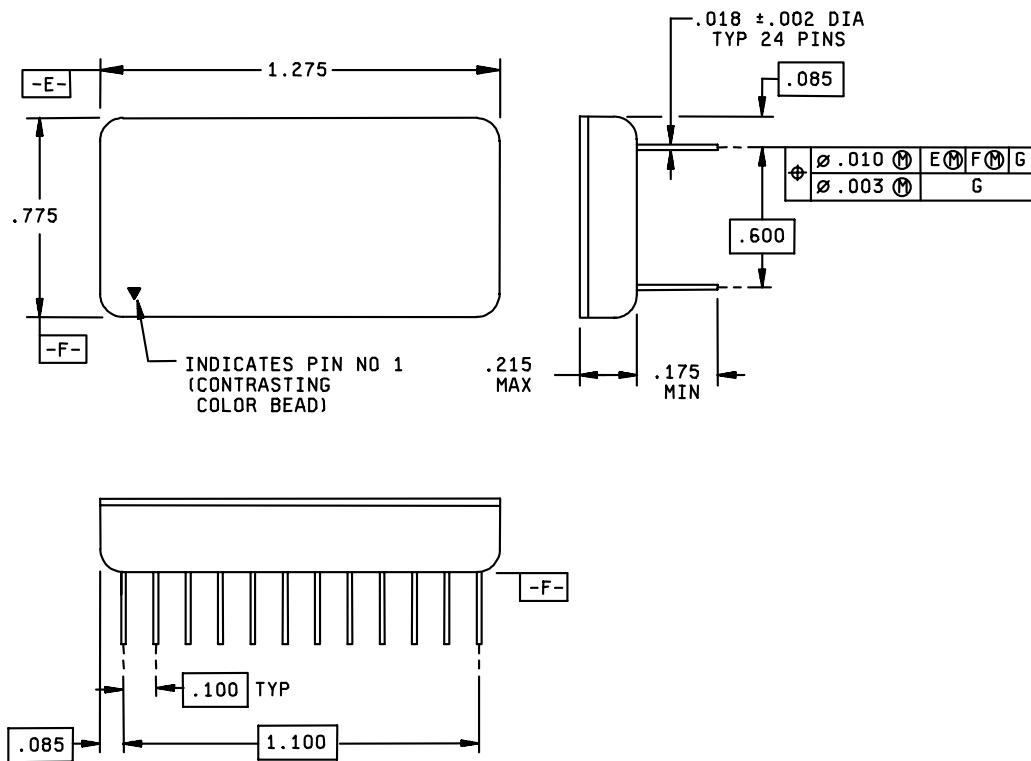
NOTES:

1. Dimensions are in inches.
2. Metric equivalents are given for general information only.
3. Lead identification numbers are for reference only.
4. Lead spacing dimensions apply only at seating plane.
5. The total number of terminals are 24.

FIGURE 1. Case outline(s) - Continued.

STANDARD MICROCIRCUIT DRAWING DEFENSE SUPPLY CENTER COLUMBUS COLUMBUS, OHIO 43216-5000	SIZE A	5962-86409
	REVISION LEVEL E	SHEET 13

Case outline Y.
(Device types 03, 05, and 06)



Inches	mm
.002	0.05
.003	0.07
.010	0.25
.018	0.45
.085	2.15
.100	2.54
.175	4.44
.215	5.45
.600	15.24
.775	19.68
1.100	27.94
1.275	32.38

FIGURE 1. Case outline(s) - Continued.

**STANDARD
MICROCIRCUIT DRAWING**

DEFENSE SUPPLY CENTER COLUMBUS
COLUMBUS, OHIO 43216-5000

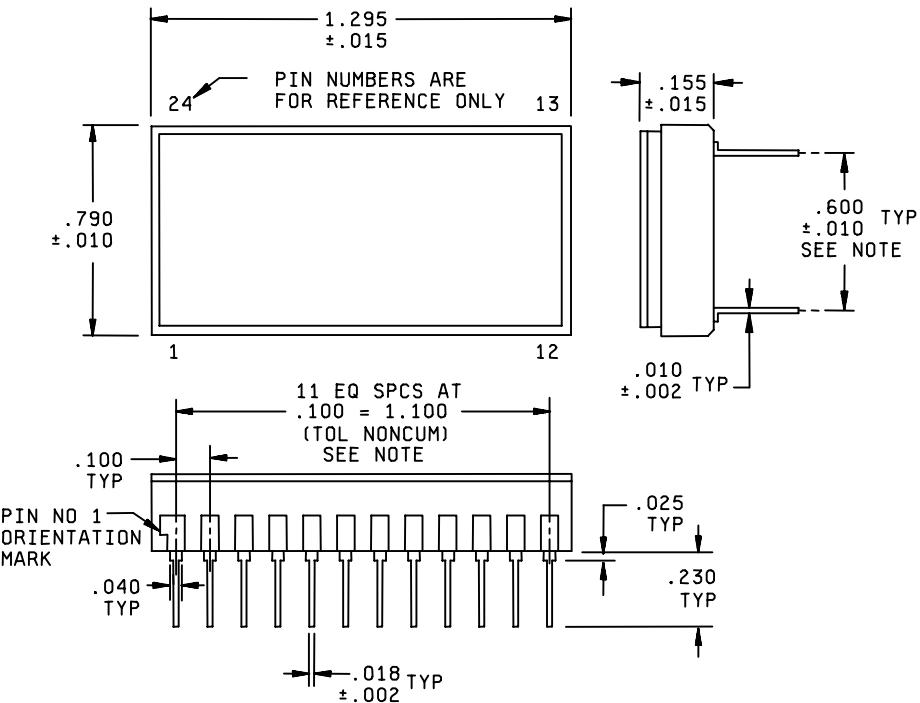
**SIZE
A**

5962-86409

REVISION LEVEL
E

SHEET
14

Case outline Z.
(Device type 02)



Inches	mm
.002	0.05
.010	0.25
.015	0.38
.018	0.46
.025	0.64
.040	1.02
.100	2.54
.155	3.94
.230	5.84
.600	15.24
.790	20.07
1.100	27.94
1.295	32.89

NOTE: Lead cluster to be centralized within ±0.010 of outline dimensions.

FIGURE 1. Case outline(s) - Continued.

**STANDARD
MICROCIRCUIT DRAWING**

DEFENSE SUPPLY CENTER COLUMBUS
COLUMBUS, OHIO 43216-5000

**SIZE
A**

5962-86409

REVISION LEVEL
E

SHEET
15

Device type	All		
Case outline	Case outlines T, U, X, Y, and Z.		
Terminal number	Terminal symbol	Terminal number	Terminal symbol
1	TX Data Out	13	V _{CC} <u>1</u> /
2	TX <u>Data</u> Out	14	No connection
3	Ground <u>1</u> /	15	RX Data Out
4	No connection	16	RX <u>Data</u> Out
5	No connection	17	No connection
6	No connection	18	Ground <u>1</u> /
7	RX Data Out	19	V _{EE} <u>2</u> /
8	Strobe	20	V _{CC1}
9	Ground <u>1</u> /	21	TX Inhibit
10	RX <u>Data</u> Out	22	TX Data In
11	No connection	23	TX <u>Data</u> In
12	No connection	24	No connection

1/ GND pins should all be connected externally. Pin 13 is +15 V dc for device types 01, 03, 04, 05, 06, 07, and 08 only, no connection for device type 02.

2/ Pin 19 for device type 06, only, no connection.

FIGURE 2. Terminal connections.

STANDARD MICROCIRCUIT DRAWING DEFENSE SUPPLY CENTER COLUMBUS COLUMBUS, OHIO 43216-5000	SIZE A	5962-86409
		REVISION LEVEL E

Device types 01 through 07.

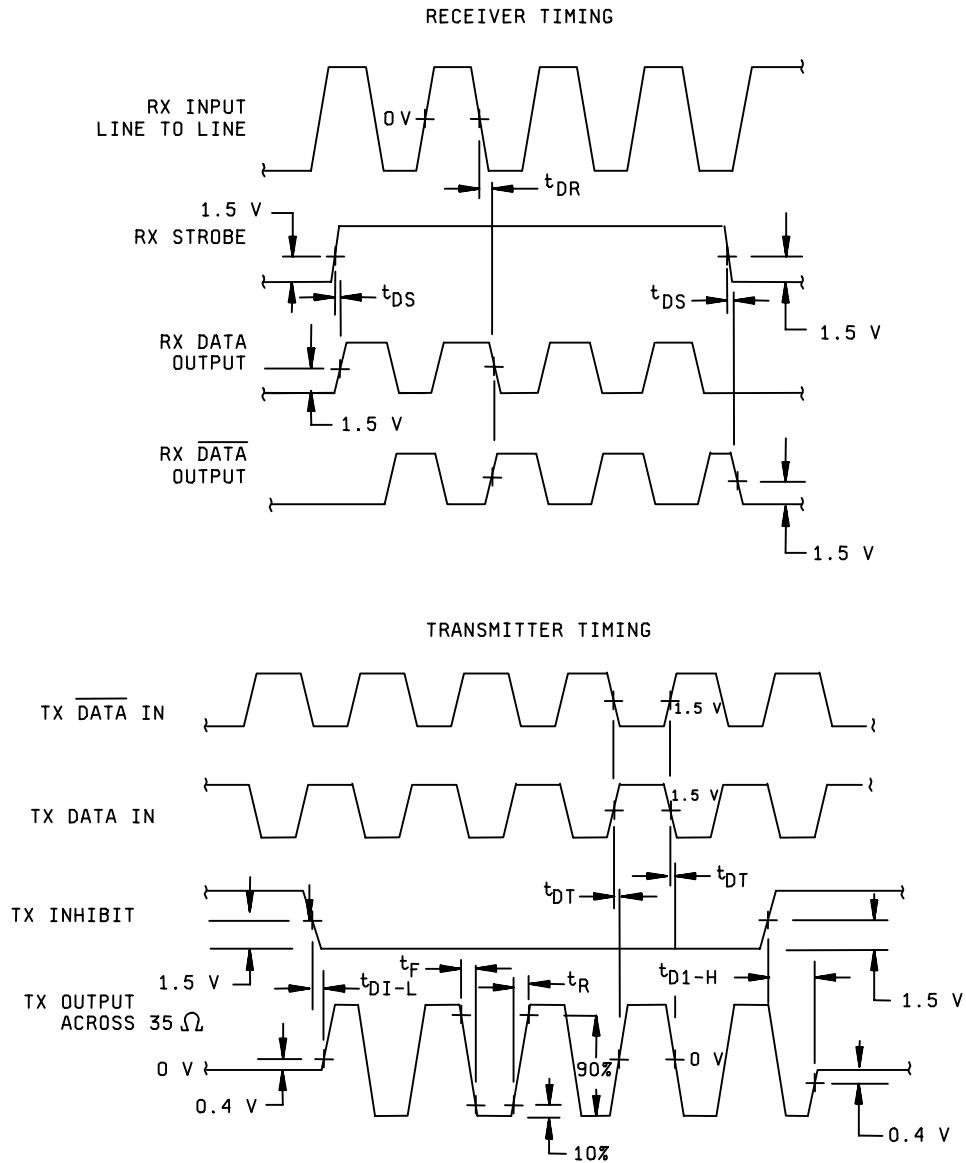


FIGURE 3. Waveforms.

**STANDARD
MICROCIRCUIT DRAWING**

DEFENSE SUPPLY CENTER COLUMBUS
COLUMBUS, OHIO 43216-5000

**SIZE
A**

5962-86409

REVISION LEVEL
E

SHEET
17

Device type 08.

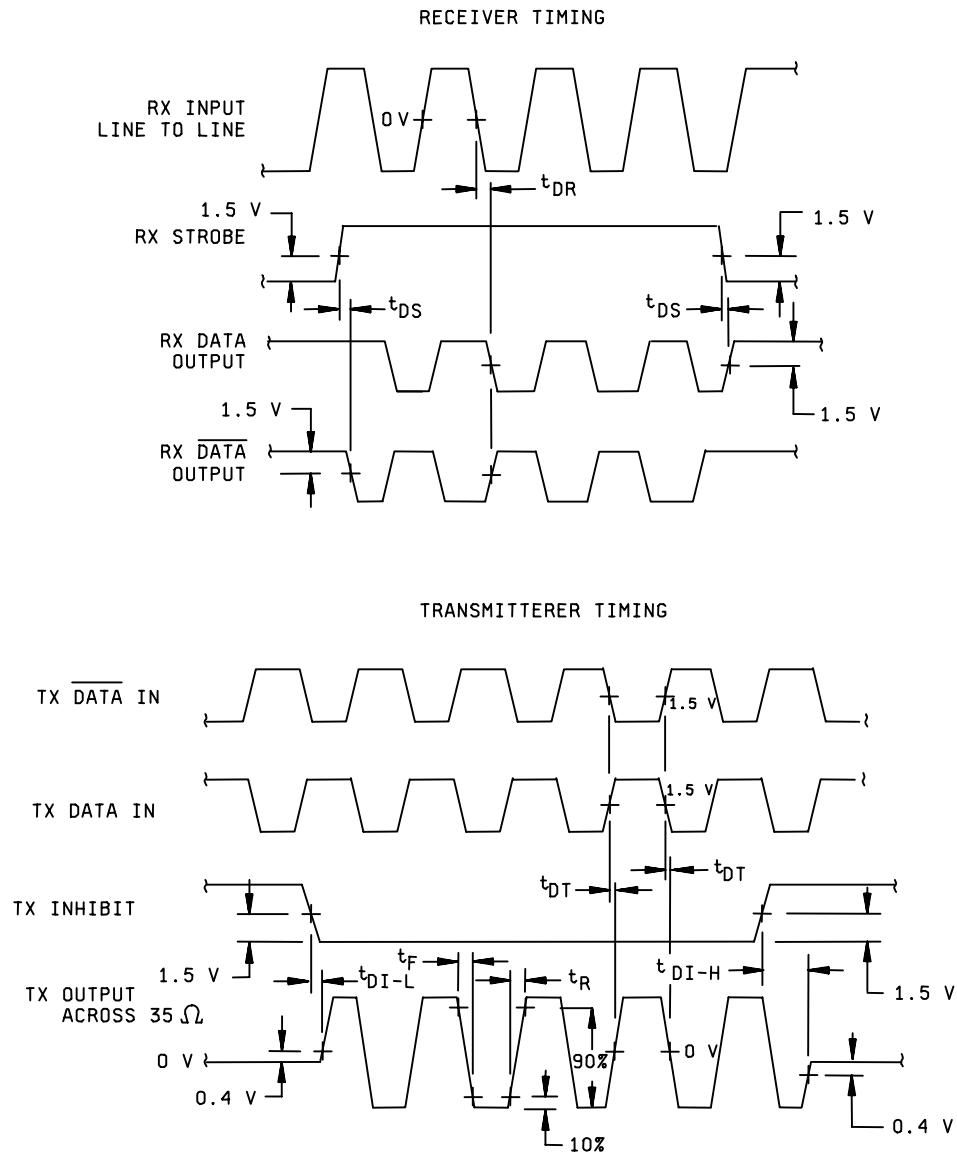


FIGURE 3. Waveforms - Continued.

**STANDARD
MICROCIRCUIT DRAWING**

DEFENSE SUPPLY CENTER COLUMBUS
COLUMBUS, OHIO 43216-5000

**SIZE
A**

5962-86409

REVISION LEVEL
E

SHEET
18

TABLE II. Electrical test requirements.

MIL-PRF-38534 test requirements	Subgroups (in accordance with MIL-PRF-38534, group A test table)
Interim electrical parameters	---
Final electrical parameters	1*,2,3,4,5,6,9,10,11
Group A test requirements	1,2,3,4,5,6,9,10,11
Group C end-point electrical parameters	1,2,3
End-point electrical parameters for radiation hardness assurance (RHA) devices	Not applicable

* PDA applies to subgroup 1.

4.3 Conformance and periodic inspections. Conformance inspection (CI) and periodic inspection (PI) shall be in accordance with MIL-PRF-38534 and as specified herein.

4.3.1 Group A inspection (CI). Group A inspection shall be in accordance with MIL-PRF-38534 and as follows:

- a. Tests shall be as specified in table II herein.
- b. Subgroups 7 and 8 shall be omitted.

4.3.2 Group B inspection (PI). Group B inspection shall be in accordance with MIL-PRF-38534.

4.3.3 Group C inspection (PI). Group C inspection shall be in accordance with MIL-PRF-38534 and as follows:

- a. End-point electrical parameters shall be as specified in table II herein.
- b. Steady-state life test, method 1005 of MIL-STD-883.

(1) Test condition A, B, C, or D. The test circuit shall be maintained by the manufacturer under document revision level control and shall be made available to either DSCC-VA or the acquiring activity upon request. Also, the test circuit shall specify the inputs, outputs, biases, and power dissipation, as applicable, in accordance with the intent specified in test method 1005 of MIL-STD-883.

(2) T_A as specified in accordance with table I of method 1005 of MIL-STD-883.

(3) Test duration: 1,000 hours, except as permitted by method 1005 of MIL-STD-883.

4.3.4 Group D inspection (PI). Group D inspection shall be in accordance with MIL-PRF-38534.

4.3.5 Radiation Hardness Assurance (RHA) inspection. RHA inspection is not currently applicable to this drawing.

STANDARD MICROCIRCUIT DRAWING DEFENSE SUPPLY CENTER COLUMBUS COLUMBUS, OHIO 43216-5000	SIZE A	REVISION LEVEL E	5962-86409
			SHEET 19

5. PACKAGING

5.1 Packaging requirements. The requirements for packaging shall be in accordance with MIL-PRF-38534.

6. NOTES

6.1 Intended use. Microcircuits conforming to this drawing are intended for use for Government microcircuit applications (original equipment), design applications, and logistics purposes.

6.2 Replaceability. Microcircuits covered by this drawing will replace the same generic device covered by a contractor-prepared specification or drawing.

6.3 Configuration control of SMD's. All proposed changes to existing SMD's will be coordinated with the users of record for the individual documents. This coordination will be accomplished in accordance with MIL-PRF-38534.

6.4 Record of users. Military and industrial users shall inform Defense Supply Center Columbus when a system application requires configuration control and the applicable SMD. DSCC will maintain a record of users and this list will be used for coordination and distribution of changes to the drawings. Users of drawings covering microelectronic devices (FSC 5962) should contact DSCC-VA, telephone (614) 692-0544.

6.5 Comments. Comments on this drawing should be directed to DSCC-VA, Post Office Box 3990, Columbus, Ohio 43216-5000, or telephone (614) 692-0536.

6.6 Sources of supply. Sources of supply are listed in MIL-HDBK-103 and QML-38534. The vendors listed in MIL-HDBK-103 and QML-38534 have submitted a certificate of compliance (see 3.7 herein) to DSCC-VA and have agreed to this drawing.

**STANDARD
MICROCIRCUIT DRAWING**
DEFENSE SUPPLY CENTER COLUMBUS
COLUMBUS, OHIO 43216-5000

SIZE A		5962-86409
	REVISION LEVEL E	SHEET 20

STANDARD MICROCIRCUIT DRAWING BULLETIN

DATE: 02-02-25

Approved sources of supply for SMD 5962-86049 are listed below for immediate acquisition information only and shall be added to MIL-HDBK-103 and QML-38534 during the next revisions. MIL-HDBK-103 and QML-38534 will be revised to include the addition or deletion of sources. The vendors listed below have agreed to this drawing and a certificate of compliance has been submitted to and accepted by DSCL-VA. This bulletin is superseded by the next dated revisions of MIL-HDBK-103 and QML-38534.

Standard microcircuit drawing PIN <u>1/</u>	Vendor CAGE number	Vendor similar PIN <u>2/</u>
5962-8604901XA	<u>3/</u>	BUS-63105
5962-8604902TC 5962-8604902TC 5962-8604902TC	S7631 S7631 S7631	BUS-63106II-110 BUS-63106II-130 BUS-63106II-601
5962-8604902TC 5962-8604902TC 5962-8604902TC	19645 19645 19645	BUS-63106II-110 BUS-63106II-130 BUS-63106II-601
5962-8604902ZA 5962-8604902ZA 5962-8604902ZA	S7631 S7631 S7631	BUS-63105II-140 BUS-63105II-150 BUS-63105II-634
5962-8604902ZA 5962-8604902ZA 5962-8604902ZA	19645 19645 19645	BUS-63105II-140 BUS-63105II-150 BUS-63105II-634
5962-8604902ZC 5962-8604902ZC 5962-8604902ZC	S7631 S7631 S7631	BUS-63105II-110 BUS-63105II-130 BUS-63105II-633
5962-8604902ZC 5962-8604902ZC 5962-8604902ZC	19645 19645 19645	BUS-63105II-110 BUS-63105II-130 BUS-63105II-633
5962-8604903YA 5962-8604903YC	88739 88739	ARX2402 ARX2402
5962-8604904UA 5962-8604904UC	88739 88739	ARX3402 ARX3402
5962-8604905XA 5962-8604905XA 5962-8604905XA	S7631 S7631 S7631	BUS-8553-140 BUS-8553-150 BUS-63100-618
5962-8604905XA 5962-8604905XA	19645 19645	BUS-8553-140 BUS-8553-150
5962-8604905XC 5962-8604905XC 5962-8604905XC	S7631 S7631 S7631	BUS-8553-110 BUS-8553-130 BUS-63100-617
5962-8604905XC 5962-8604905XC	19645 19645	BUS-8553-110 BUS-8553-130
5962-8604905YA	<u>3/</u>	CT1487M

See footnotes at end of table.

STANDARD MICROCIRCUIT DRAWING BULLETIN - Continued.

DATE: 02-02-25

Standard microcircuit drawing PIN <u>1/</u>	Vendor CAGE number	Vendor similar PIN <u>2/</u>
5962-8604906TA 5962-8604906TC	57363 57363	NHI-1509FP NHI-1509FP
5962-8604906YA 5962-8604906YC	57363 57363	NHI-1509 NHI-1509
5962-8604907XA 5962-8604907XC	K1762 K1762	FC155361 FC155361
5962-8604908XA 5962-8604908XC	K1762 K1762	FC155362 FC155362

- 1/ The lead finish shown for each PIN representing a hermetic package is the most readily available from the manufacturer listed for that part. If the desired lead finish is not listed contact the Vendor to determine its availability.
- 2/ **Caution.** Do not use this number for item acquisition. Items acquired to this number may not satisfy the performance requirements of this drawing.
- 3/ Not available from a QML supplier.

<u>Vendor CAGE number</u>	<u>Vendor name and address</u>
K1672	C-MAC Microcircuits LTD Fenner Road South Denes, Great Yarmouth NR30 3PX United Kingdom
S7631	DDC Ireland LTD. Cork Business and Technology Park Model Farm Road Cork, Ireland
19645	Data Device Corporation 105 Wilbur Place Bohemian, NY 11716-2482
57363	National Hybrid Incorporated 2200 Smithtown Avenue Ronkonkoma, NY 11779-7329
88379	Aeroflex Laboratories Incorporated 35 South Service Road Plainview, NY 11803-4101

The information contained herein is disseminated for convenience only and the Government assumes no liability whatsoever for any inaccuracies in the information bulletin.